

**Search Notes**

Application/Control No.

10/632,089

Examiner

Duc M. Nguyen

Applicant(s)/Patent under  
Reexamination

TIRKKONEN ET AL.

Art Unit

2685

**SEARCHED**

Class	Subclass	Date	Examiner
455	103 102 115.1		
	115.3.		
	450 452.2		
	504->506		
	522 67.11		
	272 273		
	63.1 423		
370	201 204		
	252 464		
	465 479		
	480		
375	298->300		
714	746		
	758 800	12/1/2005	DN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR